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	APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER				
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•	Kan Yasui Souichi Katagiri Masayuki Nagasawa Ui Yamaguchi									
`	Planarizi E	ng methoc	of sem	niconductor	wafer ar	nd apparatus thereof				

		ISSUING C	CLASSIFICATION					
ORIGINA	ORIGINAL CROSS REFERENCE(S)							
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INTERNATIONAL	CLASSIFICATION	. '.						
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1	DRAWINGS	1	CLAIMS ALLOWED		
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G	
(Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED		
			Amount Due	Date Paid	
(Primary E	Examiner)	(Date)			
			ISSUE BAT	CH NUMBER	
(Legal Instrume	ents Examiner)	(Date)			
				5, Sections 122, 181 and 38	
	(Assistant (Primary i	(Assistant Examiner) (Primary Examiner) (Logal Instruments Examiner)	(Assistant Examiner) (Date) (Primary Examiner) (Date) (Logal Instruments Examiner) (Date) stricted. Unauthorized disclosure may be prohibited by the Umark Office is restricted to authorized employees and contract	(Assistant Examiner) (Date) ISSI Amount Due (Primary Examiner) (Date)	